SN54AC00-SP Radiation Hardened Quad 2 Input NAND Gate

1 Features

- 5962R87549:
  - Radiation Hardness Assurance (RHA) up to TID 100 krad (Si)
  - SEL/SEU Immune to 86 MeV
- 5962-87549:
  - Total Ionizing Dose 50 krad (Si)
- 2-V to 6-V V_{CC} Operation
- Inputs Accept Voltages to 6 V
- Max t_{pd} of 7 ns at 5 V

2 Applications

- Satellite Payloads
- Satellite Power on Reset Logic
- RHA Known Good Die (KGD) Offering for Space Hybrids

Pin Functions (Each Gate)

INPUTS		OUTPUT Y
A	B	
H	H	L
L	X	H

Logic Diagram (Positive Logic)



3 Description

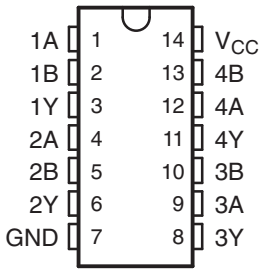
The SN54AC00 device contains four independent 2-input NAND gates. Each gate performs the Boolean function of $Y = \overline{A \cdot B}$ or $Y = \overline{A} + \overline{B}$ in positive logic.

Device Information(1)

PART NUMBER	PACKAGE	BODY SIZE (NOM)
SN54AC00-SP	CDIP (14)	5.97 mm × 9.21 mm
	CFP (14)	6.67 mm × 19.56 mm
	KGD (0)	Not applicable

(1) For all available packages, see the orderable addendum at the end of the data sheet.

J OR W PACKAGE
(TOP VIEW)



An IMPORTANT NOTICE at the end of this data sheet addresses availability, warranty, changes, use in safety-critical applications, intellectual property matters and other important disclaimers. PRODUCTION DATA.

On products compliant to MIL-PRF-38535, all parameters are tested unless otherwise noted. On all other products, production processing does not necessarily include testing of all parameters.

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4 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Revision A (December 2013) to Revision B **Page**

- Added KGD package information ... 1
- Added *Device and Documentation Support* section and *Mechanical, Packaging, and Orderable Information* section ... 1
- Added *Bare Die Information*, image, and *Bond Pad Coordinates in Microns* ... 3
- Added parameter information for KGD to *Switching Characteristics, V_{CC} = 3.3 V* and *Switching Characteristics, V_{CC} = 5 V* ... 6

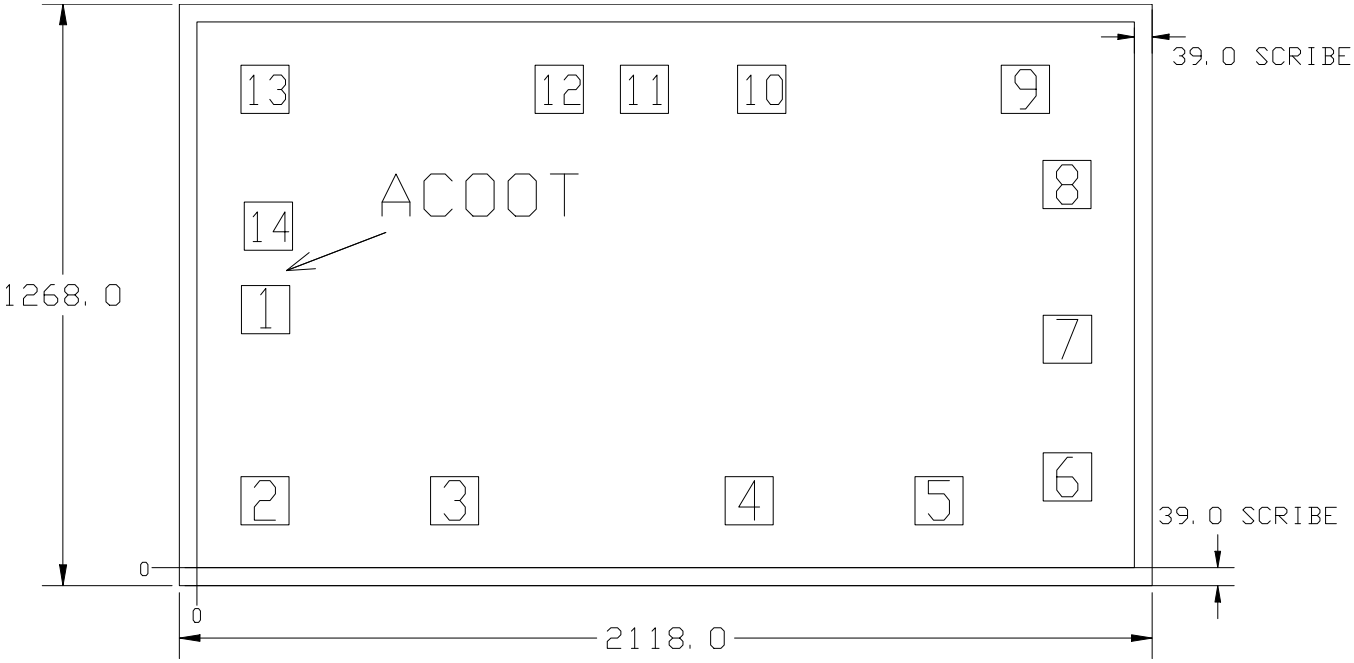
Changes from Original (October 2008) to Revision A **Page**

- Changed *Features* bullets ... 1
- Deleted *Ordering Information* table ... 1

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5 Bare Die Information

DIE THICKNESS	BACKSIDE FINISH	BACKSIDE POTENTIAL	BOND PAD METALLIZATION COMPOSITION	BOND PAD THICKNESS
15 mils	Silicon with backgrind	Floating	TiW/AlCu2	15800 nm



Bond Pad Coordinates in Microns

DESCRIPTION	PAD NUMBER	X MIN	Y MIN	X MAX	Y MAX
1A	1	96.3	510.5	201.3	615.5
1B	2	95	94	200	199
1Y	3	508	94	613	199
2A	4	1149	94	1254	199
2B	5	1562	94	1667	199
2Y	6	1841.5	145.5	1946.5	250.5
GND	7	1841.5	445.5	1946.5	550.5
3Y	8	1841	783	1946	888
3A	9	1750.5	991	1855.5	1096
3B	10	1176.5	991	1281.5	1096
4Y	11	921	991	1026	1096
4A	12	736	991	841	1096
4B	13	95	991	200	1096
VCC	14	102.5	692	207.5	797

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6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

			MIN	MAX	UNIT
V_{CC}	Supply voltage		–0.5	7	V
V_I	Input voltage(2)		–0.5	V_{CC} + 0.5	V
V_O	Output voltage(2)		–0.5	V_{CC} + 0.5	V
I_{IK}	Input clamp current	V_I < 0 or V_I > V_{CC}		±20	mA
I_{OK}	Output clamp current	V_O < 0 or V_O > V_{CC}		±20	mA
I_O	Continuous output current	V_O = 0 to V_{CC}		±50	mA
	Continuous current through V_{CC} or GND			±200	mA
T_J	Junction temperature			150	°C
T_{stg}	Storage temperature		–65	150	°C

(1) Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Conditions*. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
(2) The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

6.2 Recommended Operating Conditions

			MIN	MAX	UNIT
V_{CC}	Supply voltage		2	6	V
V_{IH}	High-level input voltage	V_{CC} = 3 V	2.1		V
		V_{CC} = 4.5 V	3.15		
		V_{CC} = 5.5 V	3.85		
V_{IL}	Low-level input voltage	V_{CC} = 3 V		0.9	V
		V_{CC} = 4.5 V		1.35	
		V_{CC} = 5.5 V		1.65	
V_I	Input voltage		0	V_{CC}	V
V_O	Output voltage		0	V_{CC}	V
I_{OH}	High-level output current	V_{CC} = 3 V		12	mA
		V_{CC} = 4.5 V		24	
		V_{CC} = 5.5 V		24	
I_{OL}	Low-level output current	V_{CC} = 3 V		12	mA
		V_{CC} = 4.5 V		24	
		V_{CC} = 5.5 V		24	
Δt/Δv	Input transition rise or fall rate			8	ns/V
T_A	Operating free-air temperature		–55	125	°C

6.3 Thermal Information

THERMAL METRIC(1)(2)		SN54AC00-SP		UNIT
		J	W	
		14 PINS	14 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	83.1	125.4	°C/W
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	26.6	30.85	
$R_{\theta JB}$	Junction-to-board thermal resistance	47.9	43.4	
ψ_{JT}	Junction-to-top characterization parameter	N/A	N/A	
ψ_{JB}	Junction-to-board characterization parameter	N/A	N/A	
$R_{\theta JC(bot)}$	Junction-to-case (bottom) thermal resistance	N/A	N/A	

(1) For more information about traditional and new thermal metrics, see the *IC Package Thermal Metrics* application report, SPRA953.
(2) The package thermal impedance is calculated in accordance with JESD 51-7 and Mil Std 883 method 1012.1 (see www.JEDEC.org).

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6.4 Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V_{CC}	T_A = 25°C			MIN	MAX	UNIT
			MIN	TYP	MAX			
V_{OH}	I_{OH} = –50 µA	3 V	2.9			2.9		V
		4.5 V	4.4			4.4		
		5.5 V	5.4			5.4		
	I_{OH} = –12 mA	3 V	2.56			2.4		
	I_{OH} = –24 mA	4.5 V	3.86			3.7		
		5.5 V	4.86			4.7		
	I_{OH} = –50 mA (1)	5.5 V				3.85		
V_{OL}	I_{OL} = 50 µA	3 V			0.1		0.1	V
		4.5 V			0.1		0.1	
		5.5 V			0.1		0.1	
	I_{OL} = 12 mA	3 V			0.36		0.5	
	I_{OL} = 24 mA	4.5 V			0.36		0.5	
		5.5 V			0.36		0.5	
	I_{OL} = 50 mA (1)	5.5 V					1.65	
I_I	V_I = V_{CC} or GND	5.5 V			±0.1		±1	µA
I_{CC}	V_I = V_{CC} or GND, I_O = 0	5.5 V			4		40	µA
C_i	V_I = V_{CC} or GND	5 V		2.6				pF

(1) Not more than one output should be tested at a time, and the duration of the test should not exceed 2 ms.

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6.5 Switching Characteristics, V_{CC} = 3.3 V

over recommended operating free-air temperature range, V_{CC} = 3.3 V ±0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	T_A = 25°C			MIN	MAX	UNIT
			MIN	TYP	MAX			
t_{PLH}	A or B	Y	2	7	9.5	1	11	ns
t_{PHL}			1.5	5.5	8	1	9	
t_{PLH} (KGD only)(1)	A or B	Y	1	7	9.5	1	11	ns
t_{PHL} (KGD only)(1)			1	5.5	9.5	1	11	

(1) Specification limits for KGD are based on SMD 5962-8754903

6.6 Switching Characteristics, V_{CC} = 5 V

over recommended operating free-air temperature range, V_{CC} = 5 V ±0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	T_A = 25°C			MIN	MAX	UNIT
			MIN	TYP	MAX			
t_{PLH}	A or B	Y	1.5	6	8	1	8.5	ns
t_{PHL}			1.5	4.5	6.5	1	7	
t_{PLH} (KGD only)(1)	A or B	Y	1.5	6	8	1	8.5	ns
t_{PHL} (KGD only)(1)			1.5	4.5	8	1	8.5	

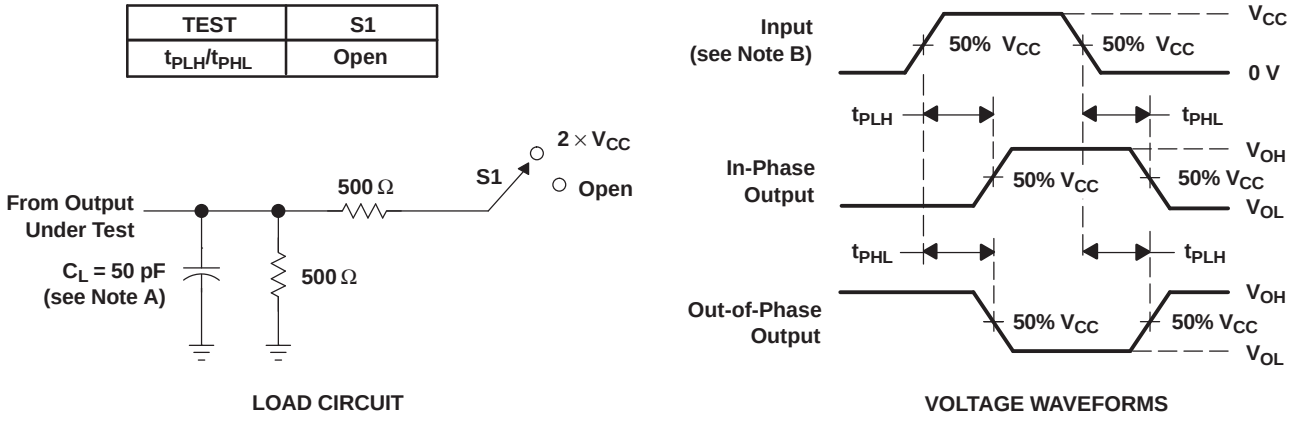
(1) Specification limits for KGD are based on SMD 5962-8754903

6.7 Operating Characteristics

V_{CC} = 5 V, T_A = 25°C

PARAMETER		TEST CONDITIONS	TYP	UNIT
C_{pd}	Power dissipation capacitance	C_L = 50 pF, f = 1 MHz	40	pF

7 Parameter Measurement Information



NOTES: A. C_L includes probe and jig capacitance.
B. All input pulses are supplied by generators having the following characteristics: PRR ≤ 1 MHz, Z_O = 50 Ω, t_r ≤ 2.5 ns, t_f ≤ 2.5 ns.
C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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8 Device and Documentation Support

8.1 Trademarks

All trademarks are the property of their respective owners.

8.2 Electrostatic Discharge Caution



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

8.3 Glossary

SLYZ022 — *TI Glossary*.

This glossary lists and explains terms, acronyms, and definitions.

9 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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